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(12) **United States Design Patent**
Chih

(10) **Patent No.:** **US D476,020 S**
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(54) **INNOVATIVE MICROMETRIC MEASURING INSTRUMENT**

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(**) Term: **14 Years**

(21) Appl. No.: **29/163,809**

(22) Filed: **Jul. 15, 2002**

(51) **LOC (7) Cl.** **16-06**
(52) **U.S. Cl.** **D16/131**; D10/46
(58) **Field of Search** D16/131; D10/46; 359/392, 368, 369

(56) **References Cited**

U.S. PATENT DOCUMENTS

D359,059 S * 6/1995 Omi D16/131
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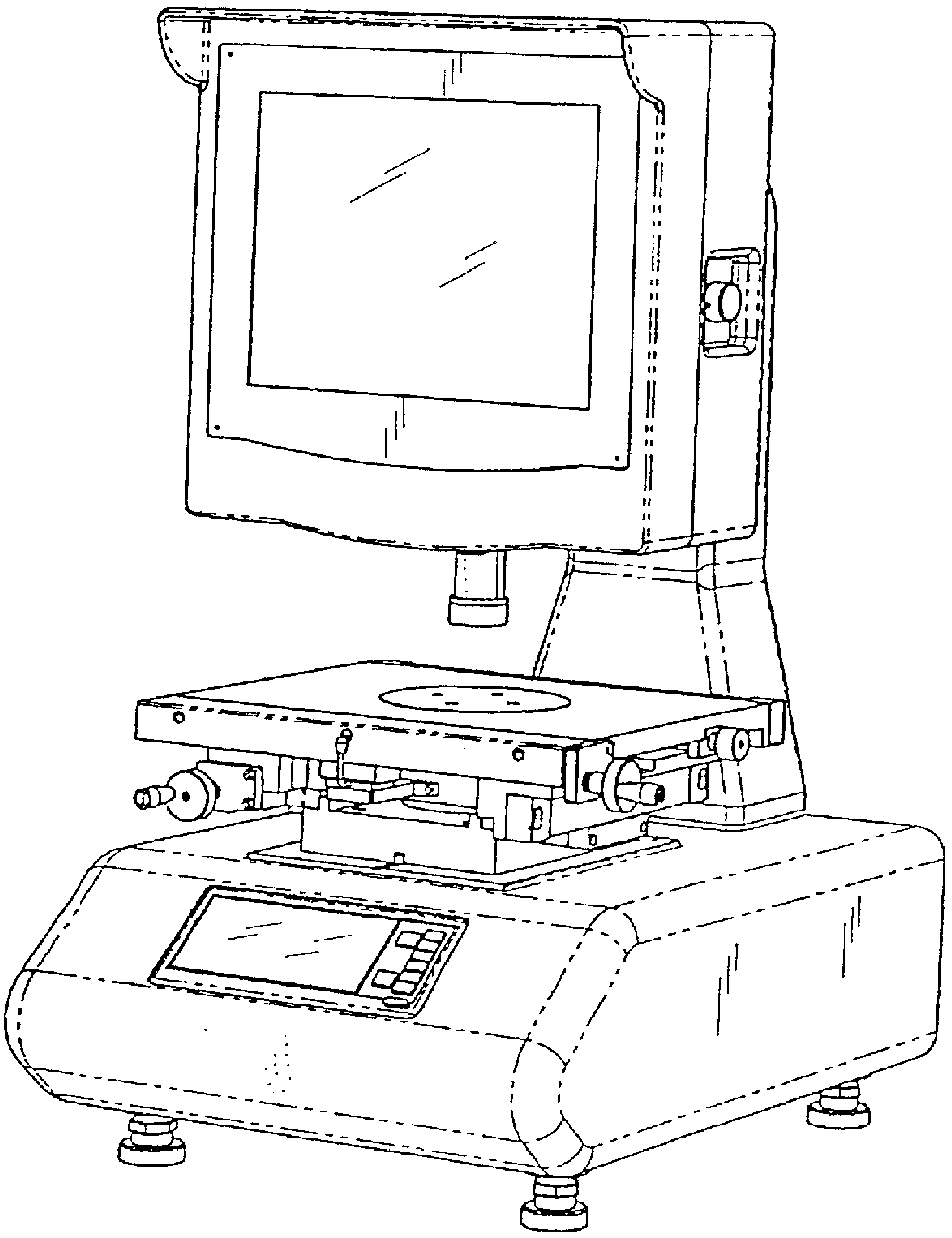
(57) **CLAIM**

The ornamental design for an innovative micrometric measuring instrument, as shown and described.

DESCRIPTION

FIG. **1** is a front elevational view of an innovative micrometric measuring instrument showing my new design;
FIG. **2** is a rear elevational view thereof;
FIG. **3** is a left side elevational view thereof;
FIG. **4** is a right side elevational view thereof;
FIG. **5** is a top plan elevational view thereof;
FIG. **6** is a bottom plan elevational view thereof; and,
FIG. **7** is a top, front and right perspective elevational view thereof.

1 Claim, 7 Drawing Sheets



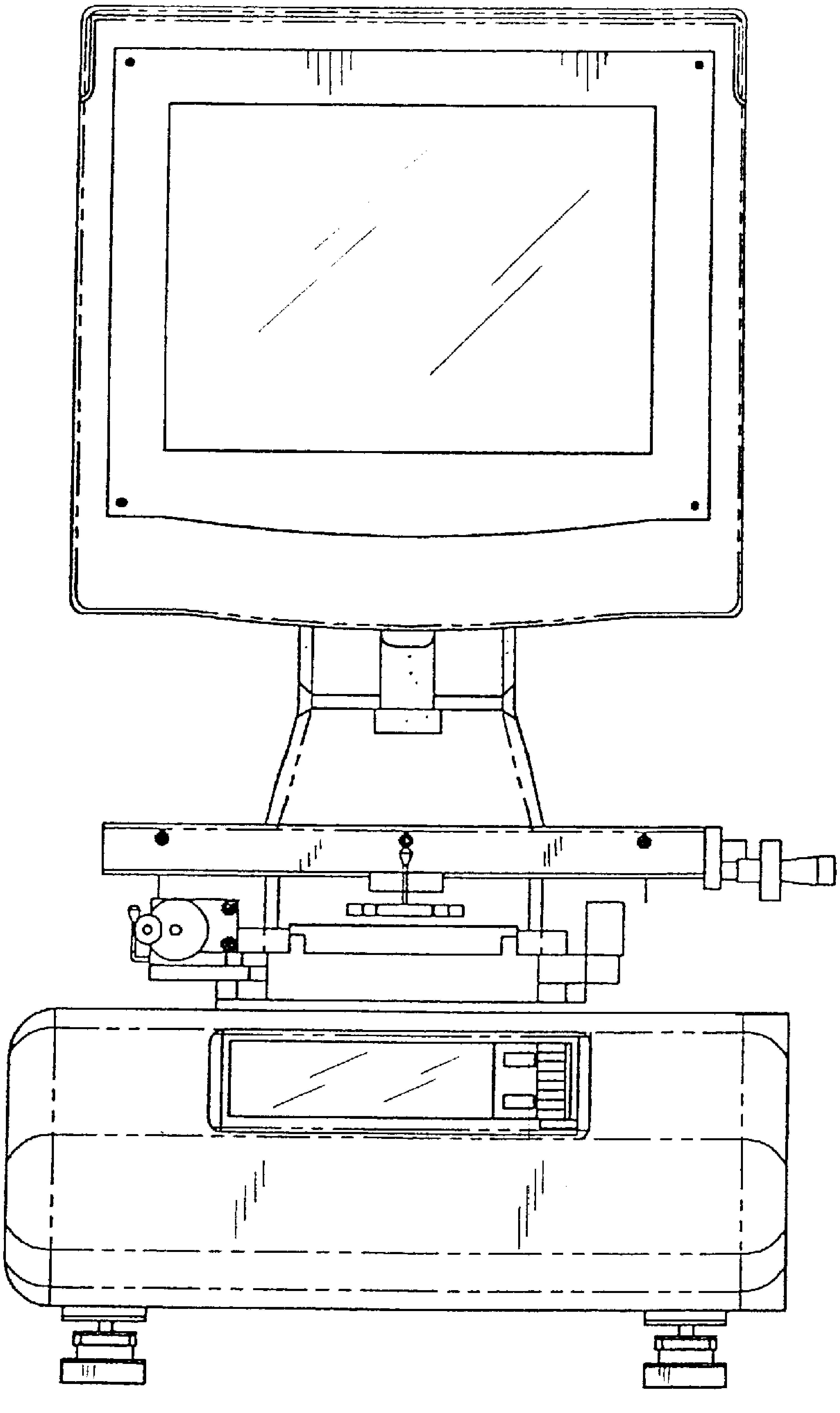


FIG. 1

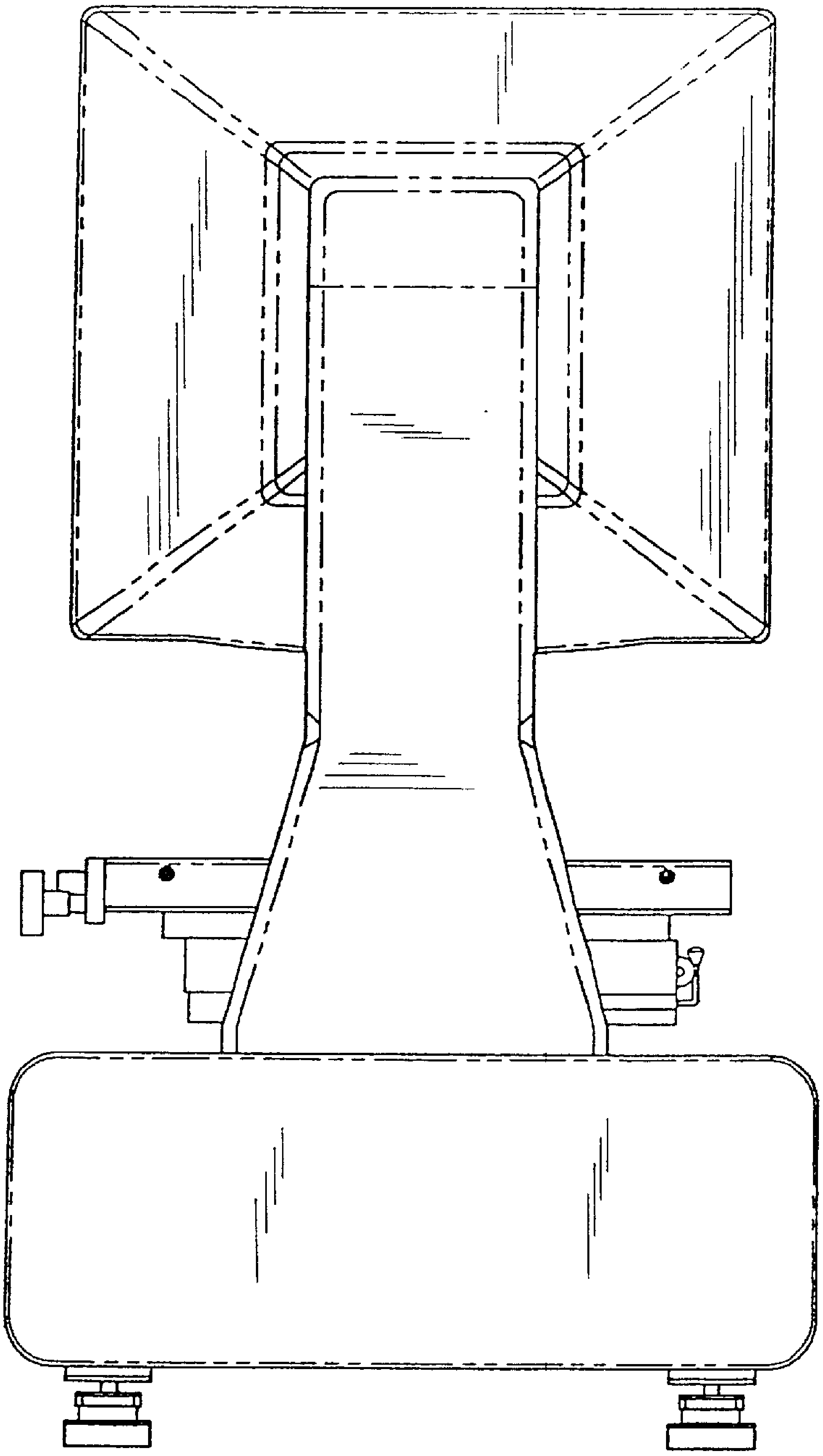


FIG. 2

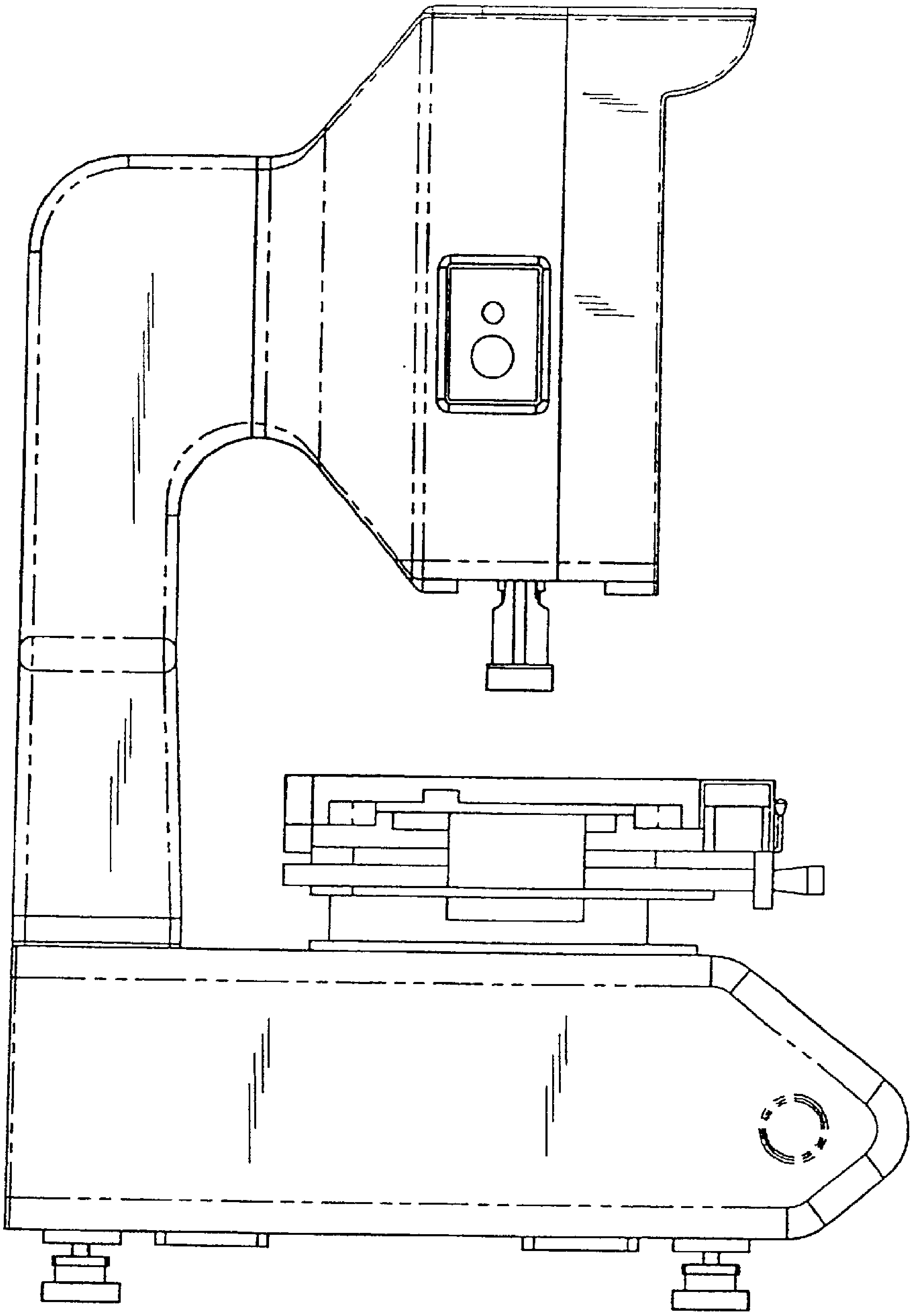


FIG. 3

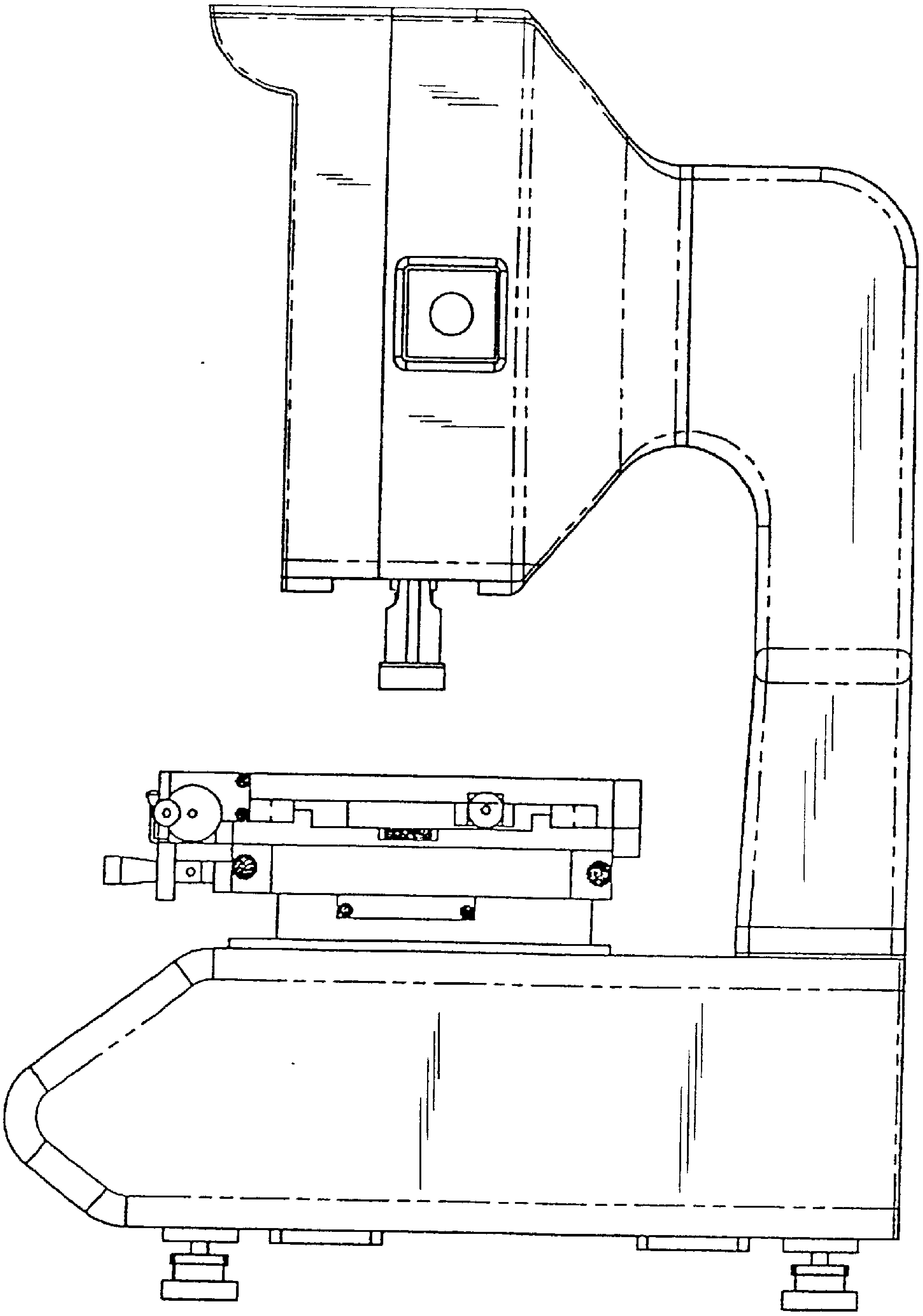


FIG. 4

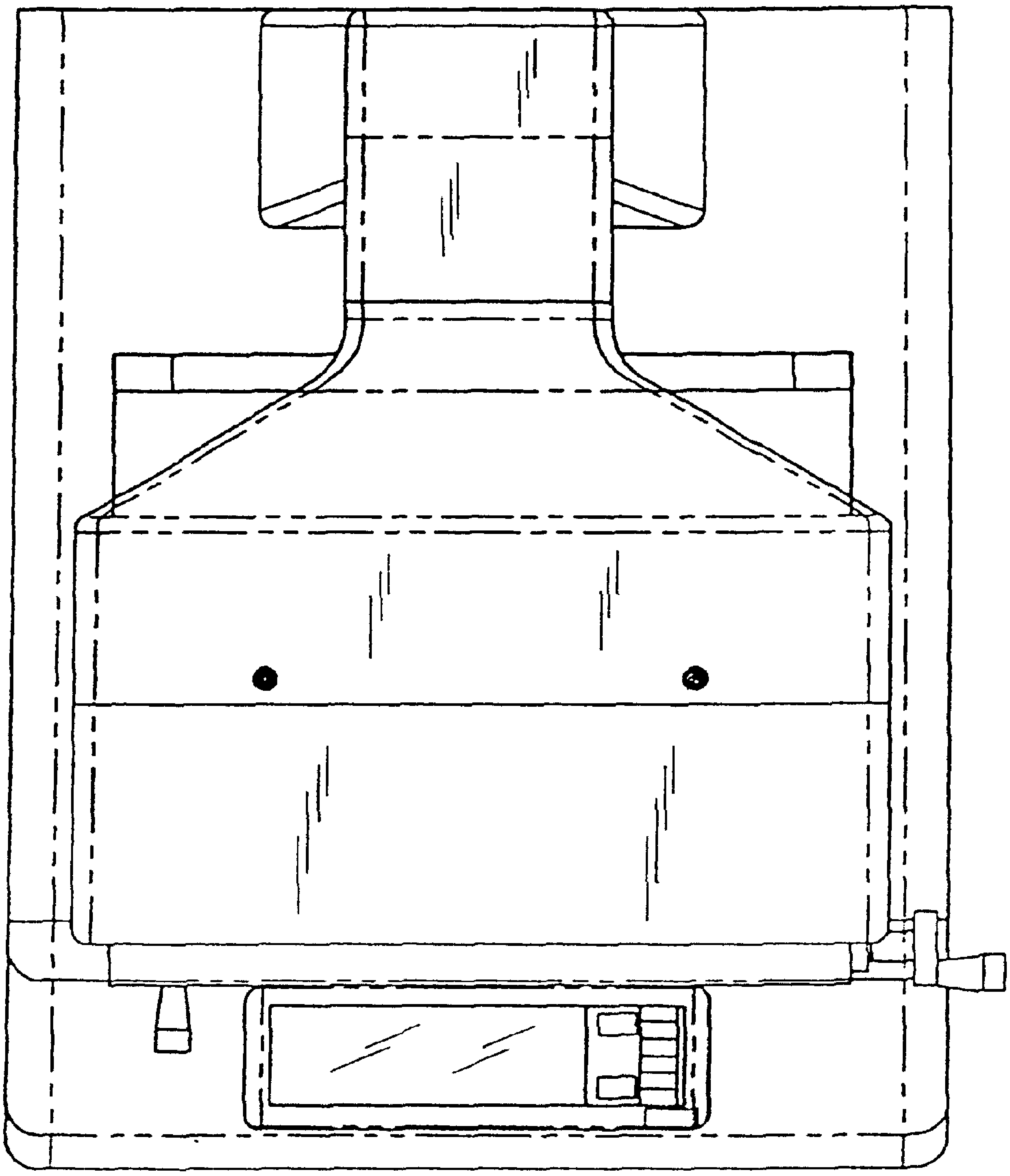


FIG. 5

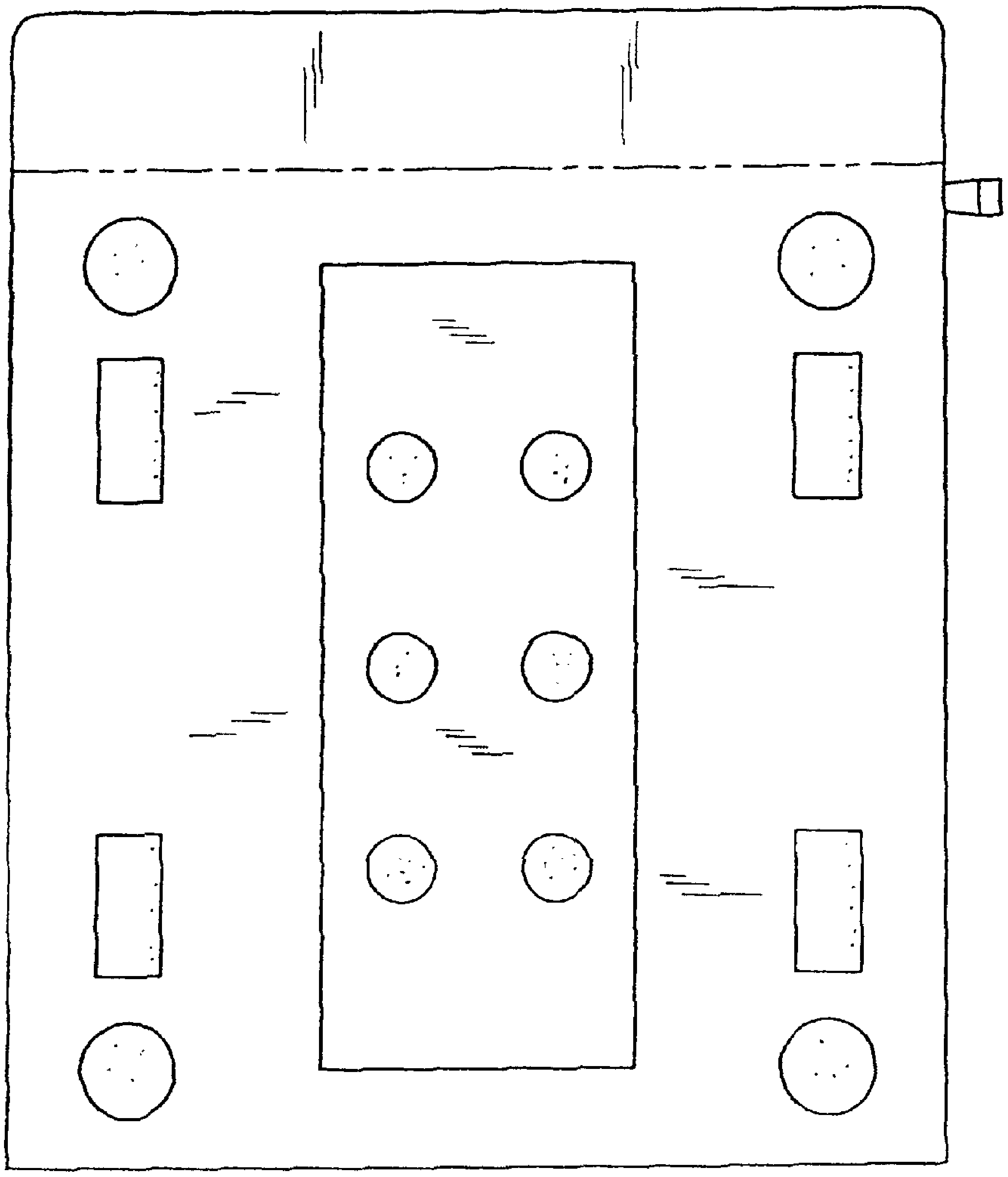


FIG. 6

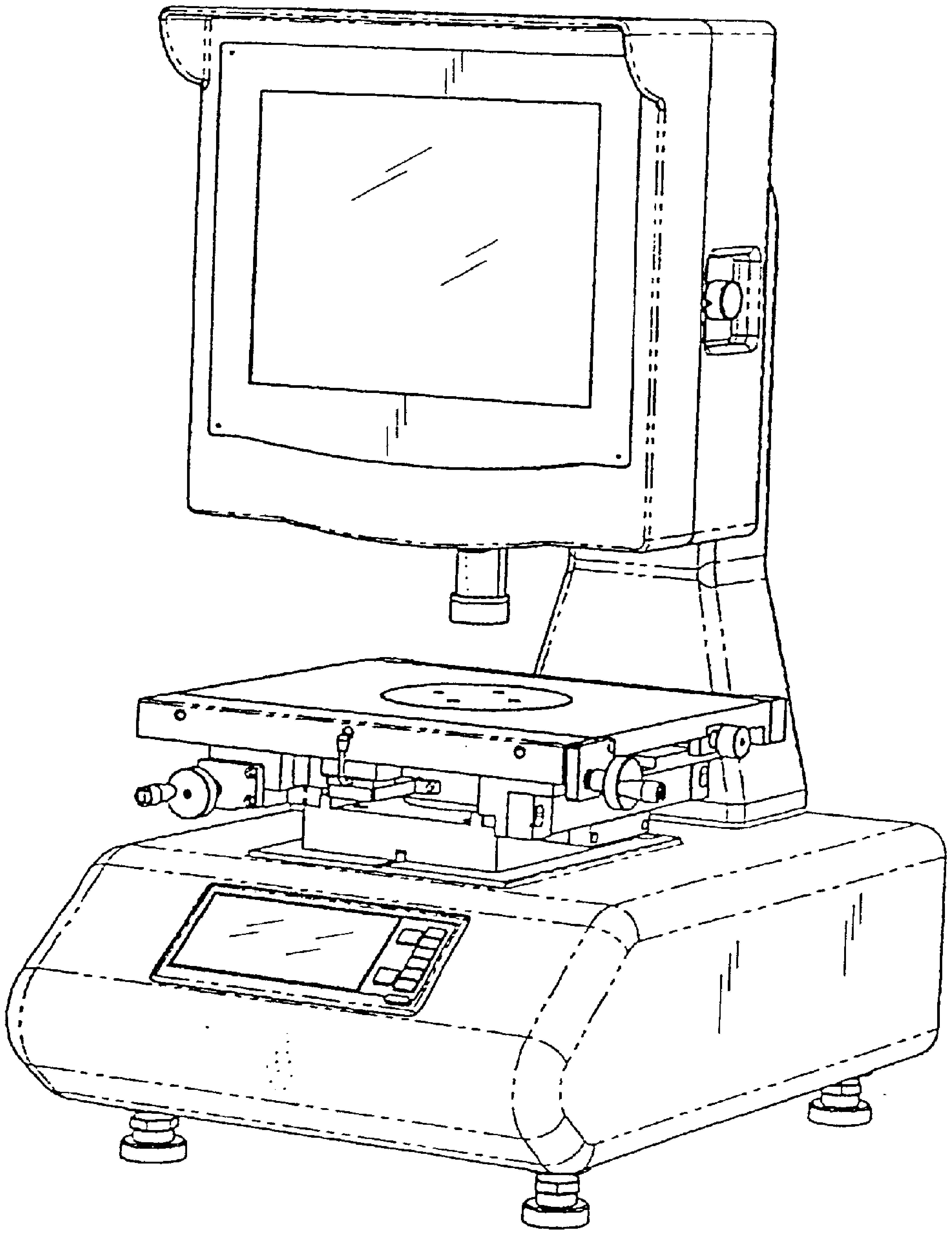


FIG. 7